## Issue Classification

App	licatio	n/Con	trol No
-----	---------	-------	---------

10650796

Examiner

Nguyen, Jennifer T

Applicant(s)/Pate	ent Under	Reexamin	atior

KODAMA ET AL.

Art Unit

2629

ORIGINAL				INTERNATIONAL CLASSIFICATION												
CLASS S		SUBCLASS	JBCLASS CLAIMED		LAIMED	NON-CLAIMED					AIMED					
345 100		G	0	9	G	3 / 36 (2006.01	1.01)			Ī						
CROSS REFERENCE(S)																
CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)																
345	87	89	98	100	204											
				-								_	_		_	
												_	_		_	
																<del> </del>
												-				
											— <del> </del> -	$\dashv$			-	
												-		_		· · · · · · · · · · · · · · · · · · ·
											$\overline{\cdot}$		1			
				,												
							·									
****			_				·									
													.			
													$\dashv$	_		
									-			-	_		_	
<del></del>												-	$\dashv$			
												+	$\dashv$			
						H		1			<del> </del> -	$\dashv$	-+			
					<del>  </del>	/,		$\sqrt{ }$			$\dashv$	$\dashv$	$\dashv$	$\dashv$		
				<del></del>		//	//	#	-		<u> </u>	$\dashv$	$\dashv$			
					<i>                                 </i>	<i>     </i>	H	1	$\overline{}$		$\dashv$	$\dashv$	$\dashv$	$\dashv$		
		<u> </u>		T	<del>' /</del> 1	#	₩,	17	_		L	- !			1	
Nauven, Jennifer T 08/15/07		- 1	/	/ ['/ / Total Claims Allowed:					lowed:							
(Assistant Examiner) (Date)		SUI	richard hjërpe Supervisory patent examiner					/INER	6							
				1 30	TECHNO!	)GY	CE	VTE	R 26	600						22215
					I E GI 10 3 C LA 10 C					11	O.G. Print Claim(s)				O.G. Print Figure	
(Legal Instr Examiner)	ruments	(Da	te)	(Primary	Examiner)				(0	Date) 8 10 07			1			5